Se	earch Notes 		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/751,469	LEE ET AL.
Examiner	Art Unit
Linh V. Nauven	2819

SEARCHED			
Class	Subclass	Date	Examiner
330	253,255 257,261 264,265	4/27/2006	LN
		<u> </u>	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		•	
PGPUB-Te) see pi	kt searched- rintout	4/27/2006	LN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East searched-see printout	4/27/2006	LN
•		9